



Ultrasonic Instrument Control and Inspection Software

- **Multiple Instrument Control** Controls up to 14 XU-2468 ultrasonic instruments.
- Time based strip charts Up to 4 dual trace strip charts.
- Run Page Test part list, with current part, part description, operator name, and Calibration setup.
- **Instrument Setup** Full feature instrument setup panels with waveform display.
- Data Bins Configure data combinations and output from the instrument and in NDT Silver.
- Security Login Two level security login feature for standard or key operators.

Device #	# ⊉ 5	Device #	Device Name	Device Type	Control Link	Waveform Link	Data Link	^
Device Name		1	Oblique22	XU-2468	RS-485 Card_1 Link: 1 · 1	Council Last	RS-485 Card_1 Link: 3 - 1	
Device Type		2	Oblique45	XU-2468	RS-485 Card_1 Link: 1 - 2	Countel Last	RS-485 Card_2 Link: 1 - 1	
Control Link	RS-485	3	Oblique67	XU-2468	RS-485 Card_1 Link: 1 - 3	Lowed Part	RS-485 Card_2 Link: 2 - 1	
	Board Address Card_1	4	Transverse	XU-2468	RS-485 Card_1 Link: 1 - 4	Lowed Part	RS-485 Card_2 Link: 3 - 1	
	Link Address \$ 5	5	Wal	XU-2468	RS-485 Card_1 Link: 1 - 5	Econol Los	RS-485 Card_2 Link: 4 - 1	
	Board Address 🗘 Card_2 Link Number 👙 4 Link Address 🗘 1	Exit Conti	1	h/Save Configurat				

Figure 1: System Configuration Panel (5 Instruments)

NDT Silver is capable of controlling, configuring and acquiring data from up to 14 Xactex XU-2468 ultrasonic flaw detectors. With 8 channels per XU-2468, this results in the possibility of 112 channels of inspection. Available control links include RS-485, RS-232, or USB and data acquisition is done via RS-485.

Silver features four, 600 point, time based strip charts. Each of these charts may have one or two traces of individually selectable colors. In addition to this there is a "Draw to Baseline" and a "Difference" option for the traces. When one of these options is enabled it allows either the area between the trace and the baseline or the area between two traces to be filled in. The difference trace is very handy for creating a wall thickness variance chart. Alarm levels may be set for each trace allowing for alarm conditions to be marked on the chart. With an adjustable time base between 50 milliseconds and 2 seconds, the data density and amount of data that is displayed can be adjusted. The charts also contain header information including the operator's ID and test part information which, is saved and recalled with the chart information. Figure 2 shows an example scan using 4 dual trace charts. Notice that the fourth chart is a difference chart.

A Run Page supplies a method of entering header and test part information. It allows the entry of a test group name and number plus a test item description and item list. In addition to this, a calibration setup feature gives an entry list for calibration part numbers and a calibration due counter/timer feature. The calibration due feature allows for a calibration due indication to occur for a number of items tested, an elapsed time between items, a total elapsed time, or any combination of the three.



Figure 2: Strip Charts





A full feature instrument setup, which includes a waveform display, gives the ability to configure and control the instruments remotely. The full color waveform display replicates the waveform on the front panel of the instrument to allow for easier setup and monitoring of the instruments. A number of setup panels give access to the various setup parameters allowing quick and easy adjustments.

In addition, a channel/gate calibration feature is available so that each gate may be checked and an individual gate calibration report can be generated. Figure 3 shows the instrument setup with waveform display and gate calibration panel. The NDT Silver software also has interfaces for configuring data bins in the instrument and in the computer. These bins are called "Instrument Bins" and "PC Bins", respectively. An instrument bin is a configuration that tells the instrument what sources that are to be combined, how to combine them, and where to output them. For example, if Gate 1 was enabled as a positive polarity flaw gate on all channels, an instrument bin could be configured to output the largest amplitude measurement taken from all those gates to the data link so that it may be acquired by Silver. A PC Bin is a similar bin that resides in the external computer/controller. Its inputs are instrument bins such as the one described above. It takes the outputted instrument bin data and can be used to further combine the data.



Figure 4: Instrument Bin Setup

For example, if there were 14 instruments in the system and they all had an instrument bin as described above then those 14 bins could be combined to find the highest reading of any Gate 1 in the system. That's the highest of 112 readings. If all gates on all channels were positive polarity flaw gates and all were combined then it would be the single highest reading

A two stage security login is built into the software to create a separation between a standard user and a key operator. This allows a foreman type person (key operator) to configure the system for the standard operators who have restricted access to the configuration areas of the software.

The software may be set so that a login is not required to access the standard level features. If required however the operators login name is automatically included on the Run Page and strip charts. A key operator login is always required to gain full access. from 448 gates. The same can be done for thickness gates allowing the thickest and thinnest measurement to be output as a single value. With this kind of versatility in configuring the sources, these bins can be setup to output nearly any desired combination of gate measurements. If uncombined data is desired, all it takes to get a single gate's measurement is to assign it as the only source for a bin.

PC Bin	Current PC Bins								
PG Dill	Content PC BIDS								
PC Bin Name:	PCbin Name	PC Operator	Instrument	Instrument Bin	Instr Operator	Bin/Array			
	Ch7+Peak	HI DETECT	Silver Test4_02	C761PK	+PEAK (Flavi)	N/A.			
	Ch7+Peak	HI DETECT	Silver_Tect4_02	C762PK	+PEAK (Flava)	N/A.			
PC Bin Operator	Ch7 +Peak	HIDETECT	Silver_Test4_02	C763PK	+PEAK (Flave)	N/A.			
HIDEFECT	Ch7+Peak	HI DETECT	Silver_Test4_02	C764PK	+PEAK (Flavi)	NA.			
	Ch8 +Peak	HI DETECT	Silver_Test4_02	C851PK	+PEAK (Flavi)	N/A.			
	Ch8+Peak	HI DETECT	Silver_Text4_02	C862PK	+PEAK (Ravi)	NAX.			
	Ch8 (Peak	HI DETECT	Silver_Test4_02	CBG3PK	+PEAK (Flave)	N/A.			
PC BIN SOURCE	Ch8+Peak	HI DETECT	Silver_Fect4_02	CEG4PK	+PEAK (Ravi)	NAN,			
rollument o n	Test +Peak	HI DETECT	Silver_Test4_02	TEST/BIN	(PEAK (Flavi)	N/A.			
	Git Low	LO DETECT	Silver_Test4_02	61L0W	LO DEFECT (FOF)	NAA.			
	G4 Low	LO DETECT	Silver_Test4_02	G4L0W	LO DETECT (TOF)	N.8A.			
Select Instrument	G4High	LO DETECT	Silver_Text4_02	G44GH	HIDETECT [TOF]	N/A.			
Silver_Fed4_02	61High	LO DETECT	Silver_Test4_02	GIHGH	HIDETECT (TOF)	N/A			
CONCERNMENTER OFFICIALIST	G4.Average	LOCK AVERAG	Silver_Text_02	644/6	AVERAGE	N/A,			
Select Bin Operator +PEAK (Flaw)	Teit/Peak	HI DETECT	Silver_Test4_02	TEST/BIN	+PEAK (Flavi)	N/A.			
Select Instrument Bin				1	1	Delete All			
G3C1+pk	Add Bin		Delete Sin		1	Quinte All			
	01.20								

Figure 5: PC Bin Setup



Communications Specifications

There is a maximum limit of 14 total instruments for the NDT Silver software. Below is a description of the available connections.

Command Link(s):

- USB 1.1: 10 instruments.
- RS-232: 14 instruments at 9.6K Baud.
- RS-485: 14 Instruments at 500K Baud. Data Link:
- RS-485: 14 instruments at 500K Baud.

Up to 14 instruments may be connected using any of the above available connections. These connection configurations may be saved and recalled allowing multiple setups to be available for recall depending on the current test.

Security Specifications

Two level security login: Level 1. Standard User, Level 2. Key Operator. Security feature may be set so that no login is required for Standard Users.

Number of Configurable Logins:

- Standard User: 30
- Key Operator: 10

Login Log

The Login Log displays the login name for the operator who is currently logged on and the last operator who was logged on.

Instrument Setup

Full function instrument setup which includes waveform display and multiple panels for setting and adjusting the various parameters of the instrument.

Instrument Bin Configuration

Configuration panel for setting up instrument bins which dictate how gate measurements are combined and output in the instrument.

PC Bin Configuration

Configuration panel for setting up PC bins which dictate how Instrument Bin data is combined in the computer/controller.

RunPage

Configuration panel and display for setting test/ header information and test item list. Includes calibration setup

Strip Charts

Configuration panel and display for up to 4 dual trace time based strip charts with individually settable trace colors. Charts include bar graph indicators for each trace and header information as well as chart alarms and the ability to save and recall.

File Save/Load

Instrument setups and system setups may be saved and recalled. This allows multiple test setups or instrument setups to be saved so that they may be recalled for review or for addition testing with the same settings.

Minimum System Requirements

- An IBM® or compatible PC
- Microsoft Windows 2000/XP
- 1GHz PIII/Celeron processor or equivalent 2GHz+ P4 recommended
- 128 MB RAM memory for Windows 2000, 256 MB for Windows XP. RAM of 512 or higher is recommended
- 5 MB of available disk space, not including storage memory
- SVGA or better color monitor with 1024 x 768 screen resolution.

For more information contact our sales department: (509)545-6364 Ext. 105 or sales@xactex.com

